

Application of Timepix Detector for Measurement of X-rays Produced by a Low-intensity Electron Beam Passing Through a Periodic Target

*A.S.Gogolev^e, A.P.Potylitsyn^e, N.A.Filatov^{e,1}, A.V.Shchagin^{a,b},
A.S.Kubankin^{b,c}, R.M.Nazhmudinov^{b,c}, S.V.Trofymenko^{a,d},
G.Kube^f, N.A.Potylitsina-Kube^f, M.Stanitzki^f, R.Diener^f,
A.Novokshonov^f*

^a NSC "Kharkiv Institute of Physics and Technology", Kharkiv, Ukraine

^b Belgorod National Research University, Belgorod, Russia

^c P.N. Lebedev Physical Institute, Moscow, Russia

^d Karazin Kharkiv National University, Kharkiv, Ukraine

^e Tomsk Polytechnic University, Tomsk, Russia

^f Deutsches Elektronen-Synchrotron (DESY), Hamburg, Germany

This report demonstrates initial testing of the high-speed spectral camera ModuPIX based Timepix detector with Si sensor. We present the first results on the measurement of X-rays produced by passing a 2 GeV low-intensity electron beam through a resonant transition radiation target and then diffracted from the HOPG crystal. A test setup was constructed on the test beam line No 21 at DESY (Hamburg, Germany). The results obtained show that the Timepix detector allows separating the low intensity diffracted X-rays from the background caused by charged particles.

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¹ Corresponding author: filatovna@tpu.ru